

<b>Notice of References Cited</b>	Application/Control No. 10/665,359		Applicant(s)/Patent Under Reexamination HEYMANS ET AL.	
	Examiner WILLIAM J. GOODCHILD		Art Unit 2145	Page 1 of 1

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#### NON-PATENT DOCUMENTS

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	U	Scarfe et al., "System and method of detecting events", International Publication Number WO 02/15479 A1, PCT/GB01/03450, February 21, 2002			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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